

SLOVENSKI STANDARD SIST EN IEC 60539-1:2023

01-april-2023

Neposredno ogrevani termistorji z negativnim temperaturnim koeficientom - 1. del: Splošna specifikacija (IEC 60539-1:2022)

Directly heated negative temperature coefficient thermistors - Part 1: Generic specification (IEC 60539-1:2022)

Direkt geheizte temperaturabhängige Widerstände mit negativem Temperaturkoeffizienten - Teil 1: Fachgrundspezifikation (IEC 60539-1:2022)

Thermistances à coefficient de température négatif à chauffage direct - Partie 1: Spécification générique (IEC 60539-1:2022)

Ta slovenski standard je istoveten z: EN IEC 60539-1:2023

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English Version

Directly heated negative temperature coefficient thermistors Part 1: Generic specification (IEC 60539-1:2022)

Thermistances à coefficient de température négatif à chauffage direct - Partie 1: Spécification générique (IEC 60539-1:2022)

Direkt geheizte temperaturabhängige Widerstände mit negativem Temperaturkoeffizienten - Teil 1: Fachgrundspezifikation (IEC 60539-1:2022)

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CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 60539-1:2023 (E)

European foreword

The text of document 40/2975/FDIS, future edition 4 of IEC 60539-1, prepared by IEC/TC 40 "Capacitors and resistors for electronic equipment" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60539-1:2023.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2023-10-19 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2026-01-19 document have to be withdrawn

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The text of the International Standard IEC 60539-1:2022 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 60027-1 NOTE Approved as EN 60027-1

ISO 80000-1 NOTE Approved as EN ISO 80000-1

EN IEC 60539-1:2023 (E)

Annex A (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	EN/HD	<u>Year</u>
IEC 60062	-	Marking codes for resistors and capacitors	EN 60062	-
IEC 60068-1	2013	Environmental testing - Part 1: General and guidance	EN 60068-1	2014
IEC 60068-2-1	Teh	Environmental testing - Part 2-1: Tests - Test A: Cold	EN 60068-2-1	-
IEC 60068-2-2	-	Environmental testing - Part 2-2: Tests - Test B: Dry heat	EN 60068-2-2	-
IEC 60068-2-6	-	Environmental testing - Part 2-6: Tests -	EN 60068-2-6	-
		Test Fc: Vibration (sinusoidal)		
IEC 60068-2-11	-	Environmental testing - Part 2-11: Tests - Test Ka: Salt mist	EN IEC 60068-2-1	1 -
IEC 60068-2-14	-	Environmental testing - Part 2-14: Tests - Test N: Change of temperature	EN 60068-2-14	-
IEC 60068-2-17	-	Basic environmental testing procedures - Part 2-17: Tests - Test Q: Sealing	EN 60068-2-17	-
IEC 60068-2-20	-	Environmental testing - Part 2-20: Tests - Test Ta and Tb: Test methods for solderability and resistance to soldering heat of devices with leads	EN IEC 60068-2-20	0 -
IEC 60068-2-21	2021	Environmental testing - Part 2-21: Tests - Test U: Robustness of terminations and integral mounting devices	EN IEC 60068-2-2	1 2021
IEC 60068-2-27	2008	Environmental testing - Part 2-27: Tests - Test Ea and guidance: Shock	EN 60068-2-27	2009
IEC 60068-2-31	-	Environmental testing - Part 2-31: Tests - Test Ec: Rough handling shocks, primarily for equipment-type specimens	EN 60068-2-31	-
IEC 60068-2-38	-	Environmental testing - Part 2-38: Tests - Test Z/AD: Composite temperature/humidity cyclic test	EN IEC 60068-2-3	8 -

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IEC 60068-2-45	1980	Basic environmental testing procedures - Part 2-45: Tests - Test XA and guidance: Immersion in cleaning solvents	EN 60068-2-45	1992
+ A1	1993		+ A1	1993
IEC 60068-2-52	-	Environmental testing - Part 2-52: Tests - Test Kb: Salt mist, cyclic (sodium chloride solution)	EN IEC 60068-2-52	2 -
IEC 60068-2-58	-	Environmental testing - Part 2-58: Tests - Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)	EN 60068-2-58	-
IEC 60068-2-69	-	Environmental testing - Part 2-69: Tests - Test Te/Tc: Solderability testing of electronic components and printed boards by the wetting balance (force measurement) method	EN 60068-2-69	-
IEC 60068-2-78	-	Environmental testing - Part 2-78: Tests - Test Cab: Damp heat, steady state	EN 60068-2-78	-
IEC 60294	-	Measurement of the dimensions of a cylindrical component with axial terminations	EN 60294	-
IEC 60717	Teh	Method for the determination of the space required by capacitors and resistors with unidirectional terminations	EN 60717	-
IEC 61193-2 https://standards	· itah oi/	Quality assessment systems - Part 2: Selection and use of sampling plans for inspection of electronic components and packages	EN 61193-2 a-92e3-eb228fc0c4	150/cist
IEC 61249-2-7	- -	Materials for printed boards and other interconnecting structures - Part 2-7: Reinforced base materials clad and unclac - Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test), copper-clad	EN 61249-2-7	- -



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Edition 4.0 2022-12

INTERNATIONAL STANDARD

NORME INTERNATIONALE

Directly heated negative temperature coefficient thermistors – Part 1: Generic specification

Thermistances à coefficient de température négatif à chauffage direct – Partie 1: Spécification générique N IEC 60539-1:2023

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

DIRECTLY HEATED NEGATIVE TEMPERATURE COEFFICIENT THERMISTORS –

Part 1: Generic specification

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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IEC 60539-1 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment. It is an International Standard.

This fourth edition cancels and replaces the third edition published in 2016. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) Restructured completely to comply to ISO/IEC directives; categorization and reorganization of test methods into these categories;
- b) Annex X added for comparison to the previous edition;
- c) Some wordings, figures and references have been revised.

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The text of this International Standard is based on the following documents:

Draft	Report on voting
40/2975/FDIS	40/3016/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

A list of all parts in the IEC 60539-1 series, published under the general title *Directly heated negative temperature coefficient thermistors*, can be found on the IEC website.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

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